Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/765,118	LEE ET AL.
Examiner	Art Unit
J. Pasterczyk	1755

	SEAR	CHED	
Class	Subclass	Date	Examiner
502	158	5/06	AP
,	159		V
	172		
	239		
	239 242 350		
	350		
923	610		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
Soz	158,159	5/06	Je	
	172,239	-		
	242, 350			
923	610			
~				

(INCLUDING SEARC	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
Inventor search	5/06	AP			